


<b>Search Notes</b>  	<b>Application/Control No.</b>  09329557	<b>Applicant(s)/Patent Under Reexamination</b>  HEINRICH ET AL.
	<b>Examiner</b>  Phu K Nguyen	<b>Art Unit</b>  2628

SEARCHED			
Class	Subclass	Date	Examiner
345	419, 420, 421, 422, 619, 620, 629, 630	11/20/08	pn

SEARCH NOTES		
Search Notes	Date	Examiner
WEST search: stochastic sampling, supersampling, subpixel, sampling pattern, Poission, distribution	11/20/08	pn
NonPatent Literature: IEEE, ACM, Google	11/20/08	pn
Inventor Name search	11/20/08	pn

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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